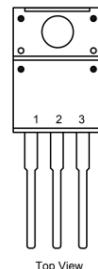
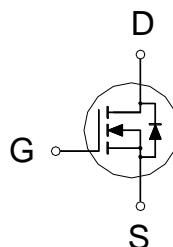


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
P1120EF
TO-220F
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
200V	280m Ω	11A


1: GATE
2: DRAIN
3: SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	200	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ C$	I_D	11	A
	$T_C = 100^\circ C$		7	
Pulsed Drain Current ¹		I_{DM}	25	
Avalanche Current		I_{AS}	13	
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	85	mJ
Power Dissipation	$T_C = 25^\circ C$	P_D	31	W
	$T_C = 100^\circ C$		12.5	
Junction & Storage Temperature Range		T_J, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W
Junction-to-Case	$R_{\theta JC}$		4	

¹Pulse width limited by maximum junction temperature.
ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ C$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	200			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	2	3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA

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Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 200V, V_{GS} = 0V$			1	μA
		$V_{DS} = 160V, V_{GS} = 0V, T_J = 125^\circ C$			10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 5.5A$		221	280	$m\Omega$
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 5.5A$		11		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 100V, f = 1MHz$		547		pF
Output Capacitance	C_{oss}			57		
Reverse Transfer Capacitance	C_{rss}			16		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		2.8		Ω
Total Gate Charge ²	Q_g	$V_{DS} = 100V, I_D = 11A, V_{GS} = 10V$		16		nC
Gate-Source Charge ²	Q_{gs}			2.1		
Gate-Drain Charge ²	Q_{gd}			6.9		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DS} = 100V, I_D \geq 11A, V_{GS} = 10V, R_{GEN} = 6\Omega$		7		nS
Rise Time ²	t_r			26		
Turn-Off Delay Time ²	$t_{d(off)}$			24		
Fall Time ²	t_f			41		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current ³	I_S				11	A
Forward Voltage ¹	V_{SD}	$I_F = 11A, V_{GS} = 0V$			1.2	V
Diode Reverse Recovery Time	t_{rr}	$I_F = 11A, dI/dt = 100A/\mu s$		125		nS
Diode Reverse Recovery Charge	Q_{rr}			559		

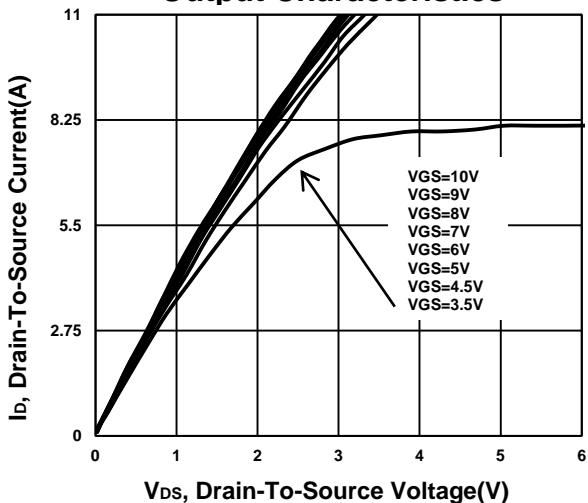
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.

NIKO-SEM

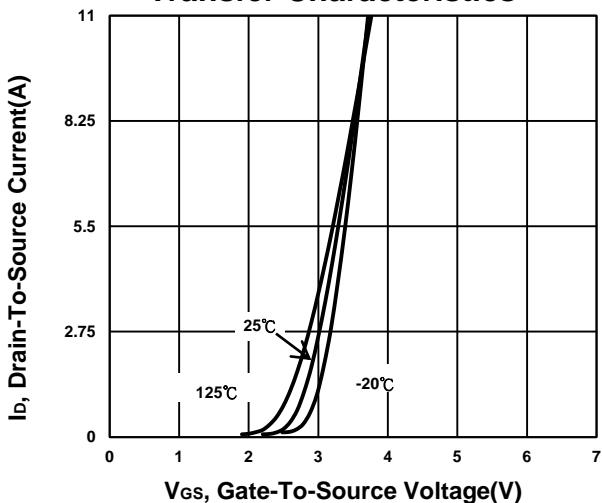
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Field Effect Transistor**

P1120EF
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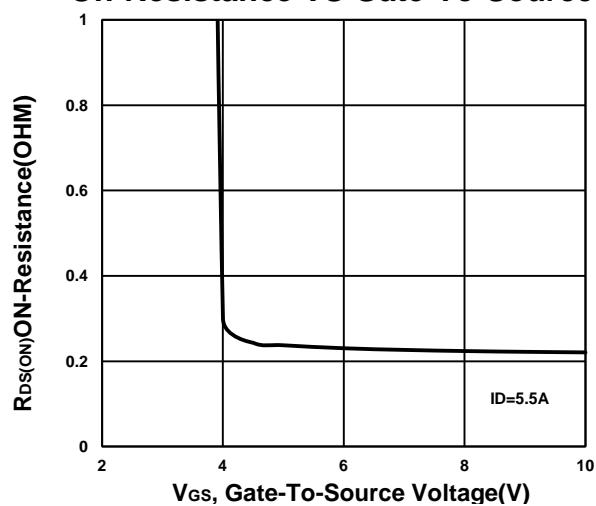
Output Characteristics



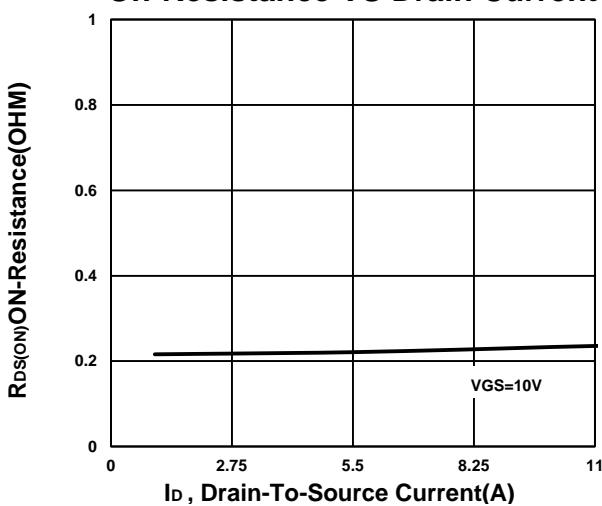
Transfer Characteristics



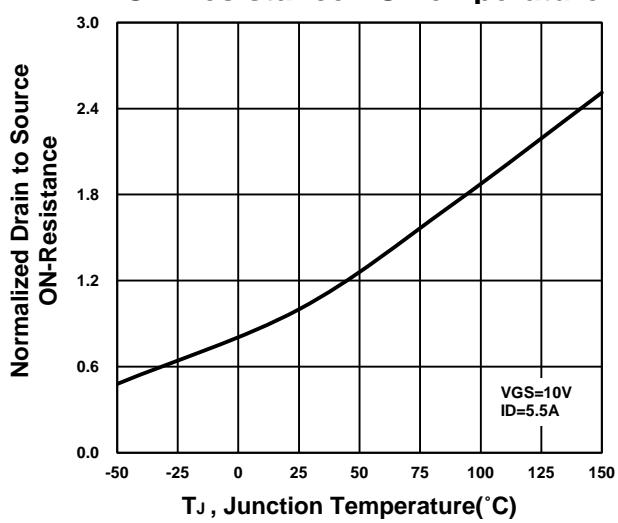
On-Resistance VS Gate-To-Source



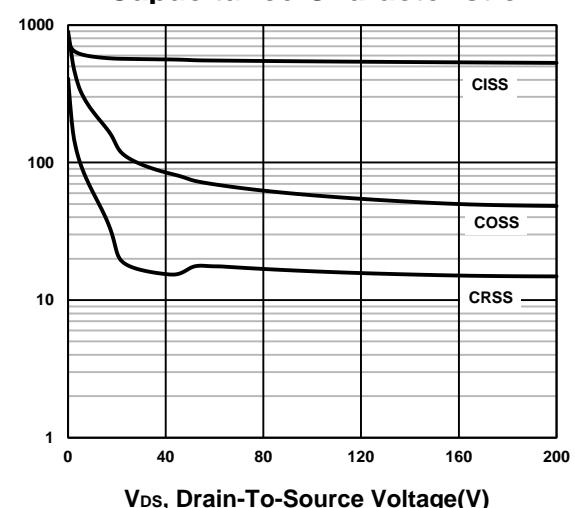
On-Resistance VS Drain Current

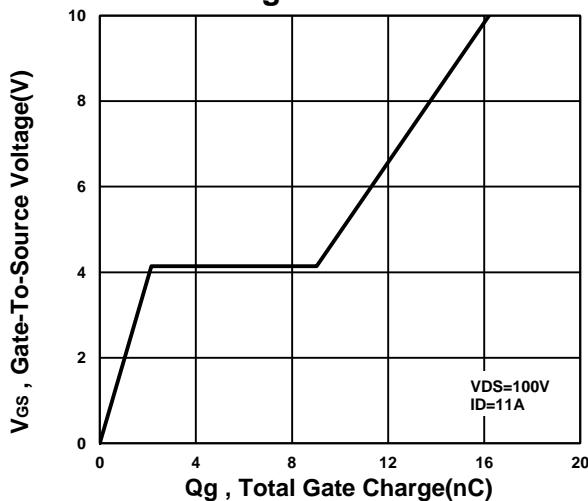
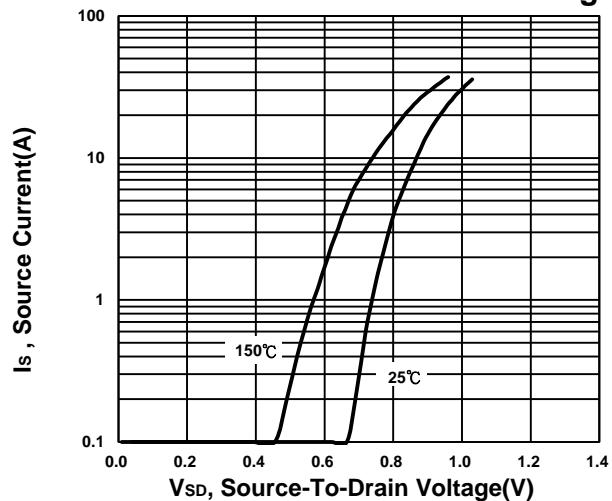
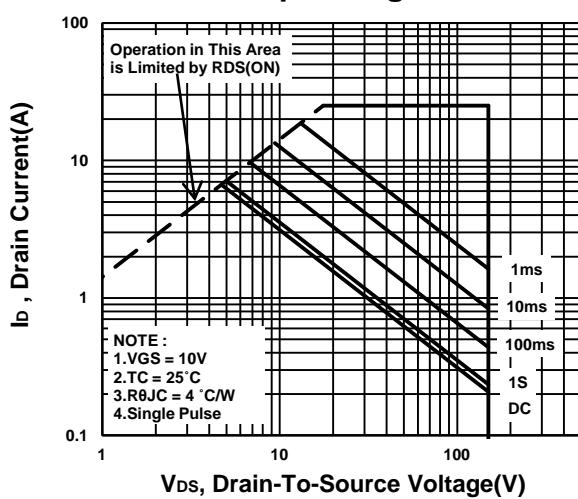
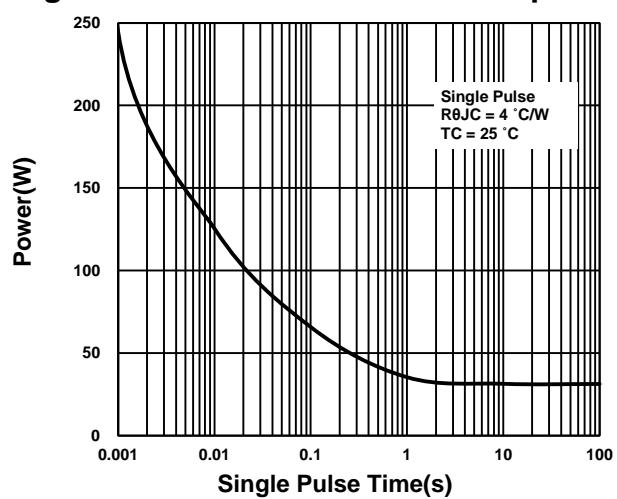


On-Resistance VS Temperature



Capacitance Characteristic



NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****P1120EF**
TO-220F
Halogen-Free & Lead-Free**Gate charge Characteristics****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**